



<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10618343</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>UNO, KOUJI</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>


Class	SubClass	Date	Examiner
324	403	08/11/2006	HK
340	815.52	08/11/2006	HK
340	815.75	08/11/2006	HK

U.S. Patent and Trademark Office	Part of Paper No.: 2006081132
----------------------------------	-------------------------------

<b>Search Notes</b>  	Application/Control No.  10618343	Applicant(s)/Patent Under Reexamination  UNO, KOUJI
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
EAST (US-PGPUB,USPAT,USOCR,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	08/11/2006	HK

U.S. Patent and Trademark Office	Part of Paper No.: 2006081132
----------------------------------	-------------------------------

<b>Interference Searched</b>  	Application/Control No.  10618343	Applicant(s)/Patent Under Reexamination  UNO, KOUJI
	Examiner Kaplan, Hal I	Art Unit 2836

Class	SubClass	Date	Examiner
Interference Search History		08/11/2006	HK
Printout			
U.S. Patent and Trademark Office		Part of Paper No.:	2006081132